

Report No: S210319134Ver:A

ELECTROSTATIC DISCHARGE (ESD) TESTING REPORT

Applicant/Department: Nations Technologies Inc.					
Product: N32G030F6S7	LOT:				
Case NO: S210319134	Quantity: 3 ea				
Test Item: CDM	Package/Pin Count: TSSOP20				
Application Date: 2021/3/19	Date Finished: 2021/3/30				
Reference: ESDA/JEDEC JS-002-2018	Temperature: 25 ± 5 °C Humidity: $55 \pm 5\%$				
Test Instrument: Orion(SN1612241)	Calibiration Due Date: 2020/08/31~2021/08/30				
Test Voltage: ±1000V					
Failure Criteria:					
compliance within 10% V+I envelope around REFERENCE I-V curve (pre-zap) and Customer FunctionTest.					
ESD Testing Result: Minimum Pass Level = ±1000V					

NOTE 1: ESD/latch-up test is employed as one of qualification tests for electronic products.

However, the pass / fail results of this test can NOT be taken as go/no-go criteria for IC tape-out and mass production. Before and after ESD/latch-up test(s), complete parametric and functional testing (F/T) are essential for determining pass/fail of the tested products. (References: Page 9, AEC-Q100-003-Rev-E-2003;

and Page 15, ESDA-JEDEC JS-001-2017).

NOTE 2: MA-tek sample storage policy is 14 days after the test data delivery. Prolonged

storage can be arranged per client's request.

WE HEREBY CERTIFY THAT:

The test(s) was/were conducted according to test conditions provided by customer. Testing was performed on calibrated and JEDEC-ESDA qualified ESD instruments. The quality and comprehensiveness of this test(s) were delivered by qualified personnel.

	Jels Technology
Tested by	Reviewed by
Joe_Xu	Fly- Fei Spenen-Hu

CERTIFICATE of APPROVAL INDEPENDENT TESTING LABORATORY:

ISO9001:2015 Certificate Registration No. 20001845 QM08, issued by UL DQS Inc. IEC/IECQ17025 Certificate No. IECQ-L ULTW 09.0009, approved by Certification Body (CB): UL Registered Firm





Report No: S210319134Ver:A

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- 1.遵守国家法律、法规和认可机构的要求,执行分析检测服务;
- 2.坚持独立检测、独立判断,保持和发展认可的分析检测能力;
- 3.坚持公平、公正、对所有客户一视同仁的分析检测服务原则:
- 4.不从事与客户送检产品相关的研发、生产、销售等活动;
- 5.不接受有违分析检测公正性的投资赞助和代理要求,不介入客户之间的市场竞争和利益冲突;
- 6.维护客户的权利,保护客户的所有权和专利权不受侵犯。

保护客户机密讯息和所有权的承诺 Confidentiality

实验室承诺保护客户的机密讯息和所有权。客户提供的分析检测方法、技术要求和图面文件、说明书以及委托合约和协议等与分析检测有关的所有文件及受检样品、检测结果均列入实验室保密范畴,以及保护客户所有权的完整性。在主持能力验证和分包检测时,也为参加实验室及客户的检测数据及结果保密。





Report No: S210319134Ver:A

TABLE OF CONTENTS

- 1. TEST SUMMARY
- 2. PIN ASSIGNMENT
- 3. ESD TESTING CONDITIONS
- 4. RAW DATA
- 5. APPENDIX-1 (PASS/FAIL CRITERIA)
- 6. APPENDIX-2 (ESD INSTRUMENTATION AT MA-TEK)





Report No: S210319134 Ver:A

1. TEST SUMMARY

	Pin Combination	Sample	Pass Level
	All pins(±)	3	±1000V
Sensitivity Pass: ±1000V			
Class-C3			
SDA/JEDEC JS-002-2018			
COA : < 125 V			
COB : 125 V - < 250 V			
:1 : 250 V - < 500 V			
22A: 500 V - < 750V			
C2B: 750 V - < 1000V			
3 : >= 1000 V			
			
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^{*} DUT failed at the first level of test condition, defined by client.

NOTE: Red color in raw data indicates failed pins, if any.





Report No: S210319134Ver:A

2. Pin ASSIGNMENT

Pin Group	PAD Pins
VDD	16
VSS	15
Ю	1-14,17,18,19,20





Report No: S210319134Ver:A

3. ESD TEST CONDITIONS

ESD Zap Interval: ≥ 200 ms Zap: 3 pulse.

Testing Combinations

All pins(±)





Report No: S210319134Ver:A

4. Raw Data - 2

CDM All pins Test_±1000 (Unit: V)									
Test Pin Fail Voltage #19 #20 #21 Test Pin Fail Voltage			st Pin Fail Voltage	#19	#20	#21			
	VDD	Pass	Pass	Pass		Ю	Pass	Pass	Pass
	VSS	Pass	Pass	Pass					

Report No: S210319134Ver:A

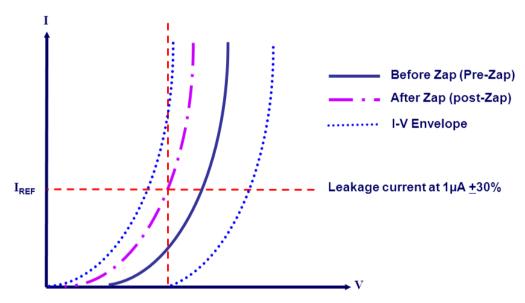
5. APPENDIX-1 (PASS/FAIL CRITERIA)

FAILURE CRITERIA

compliance within 10% V+I envelope around REFERENCE I-V curve (pre-zap) and Customer FunctionTest.

Note

For custom designed ESD testing customers may select variation in Idd, and leakage current as criteria to determine pass/fail results of ESD testing.

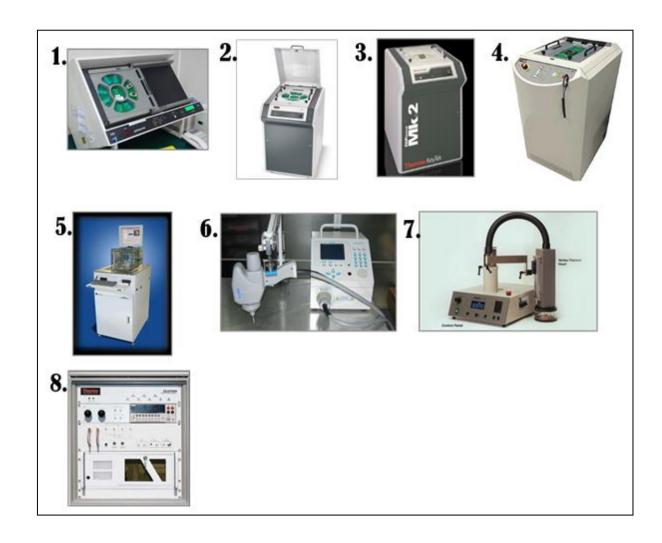


Pass/Fail Criteria: Variation of Leakage Current and I-V Shift in Pre-Zap and Post-Zap curves

Report No: S210319134Ver:A

6. APPENDIX-2 (ESD INSTRUMENTATION AT MA-TEK)

No.	Test Tools	Vendors	System Specification
1	Zapmaster	Thermo Keytek	256 Pin Count, ESD Pulse 50 V to 8 KV
2	MK1	Thermo Scientific	256 Pin Count, ESD Pulse 10 V to 8 KV
3	MK2	Thermo Keytek	768 Pin Count, ESD Pulse 10 V to 8 KV
4	MK4	Thermo Scientific	2304 Pin Count, ESD Pulse 10 V to 8 KV
5	CDM Tester	Oryx Orion	100 V to 2 KV
6	ESD Gun	Noiseken	Voltage = 1 KV to 30 KV
7	High Temp. Test Module	Thermonics	Maximum temperature = 150°C.
8	TLP Tester	Thermo Scientific	Voltage = 1 V to 2 KV, Current = 10 nA to 40 A





Report No: S210319134Ver:A

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